

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	489	((array or plural\$5) adj30 (charged or electron\$1 or ion\$1) adj30 beams) and ((lens\$3 or coil \$1) adj30 (imag\$5 or focus\$5) adj30 beams) and (accelerat \$5 adj30 beams) and ((voltage\$1 or potential\$1) adj30 (specimen\$1 or sample\$1 or wafer\$1 or substrate\$1 or circuit\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/17 13:33
L2	96	((array or plural\$5) adj30 (charged or electron\$1 or ion\$1) adj30 beams) and ((lens\$3 or coil \$1) adj30 (imag\$5 or focus\$5) adj30 beams) and (accelerat \$5 adj30 beams) and ((voltage\$1 or potential\$1) adj30 (specimen\$1 or sample\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/17 13:35

		or wafer\$1 or substrate\$1 or circuit\$3)) and (extract\$5 adj30 beams) and (angl\$5 adj30 beams)				
L3	90	((array or plural\$5) adj30 (charged or electron\$1 or ion\$1) adj30 beams) and ((lens\$3 or coil \$1) adj30 (imag\$5 or focus\$5) adj30 beams) and (accelerat \$5 adj30 beams) and ((voltage\$1 or potential\$1) adj30 (specimen\$1 or sample\$1 or wafer\$1 or substrate\$1 or circuit\$3)) and (extract\$5 adj30 beams) and (angl\$5 adj30 beams) and (deflect\$5 adj30 beams)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/17 13:37
L4	24	((array or plural\$5) adj30 (charged or electron\$1 or ion\$1) adj30 beams) and ((lens\$3 or coil \$1) adj30 (imag\$5 or focus\$5) adj30 beams) and (accelerat	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/17 13:41

		\$5 adj30 beams) and ((voltage\$1 or potential\$1) adj30 (specimen\$1 or sample\$1 or wafer\$1 or substrate\$1 or circuit\$3)) and (extract\$5 adj30 beams) and (angl\$5 adj30 beams) and (deflect\$5 adj30 beams) and (electrode \$1 adj30 vacuum)				
L5	20	((array or plural\$5) adj30 (charged or electron\$1 or ion\$1) adj30 beams) and ((lens\$3 or coil \$1) adj30 (imag\$5 or focus\$5) adj30 beams) and (accelerat \$5 adj30 beams) and ((voltage\$1 or potential\$1) adj30 (specimen\$1 or sample\$1 or wafer\$1 or substrate\$1 or circuit\$3)) and (extract\$5 adj30 beams) and (angl\$5 adj30 beams) and (deflect\$5 adj30 beams) and (electrode \$1 adj30	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/17 14:57

		vacuum) and (energ\$3 adj30 (fact\$5 or high\$5 or low\$5 or great \$5 or less or small\$5))				
L6	1	((array or plural\$5) adj30 (charged or electron\$1 or ion\$1) adj30 beams) and ((lens\$3 or coil \$1) adj30 (imag\$5 or focus\$5) adj30 beams) and (accelerat \$5 adj30 beams) and ((voltage\$1 or potential\$1) adj30 (specimen\$1 or sample\$1 or wafer\$1 or substrate\$1 or circuit\$3)) and (extract\$5 adj30 beams) and (angl\$5 adj30 beams) and (deflect\$5 adj30 beams) and (electrode \$1 adj30 vacuum) and (energ\$3 adj30 (fact\$5 or high\$5 or low\$5 or great \$5 or less or small\$5))). clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/17 15:06

11/17/08 3:09:37 PM

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